

## FEATURES

- Single Supply 3.3V or  $\pm 3.3V$  Operation
- Built-In Sample-and-Hold
- Direct 3-Wire Interface to Most MPU Serial Ports and All MPU Parallel Ports
- 30kHz Maximum Throughput Rate

## KEY SPECIFICATIONS

- Minimum Guaranteed Supply Voltage: 2.7V
- Resolution: 12 Bits
- Fast Conversion Time: 24 $\mu$ s Max Over Temp.
- Low Supply Current: 1.0mA

## TYPICAL APPLICATION

- Battery-Powered Instruments
- Data Logger
- Data Acquisition Modules

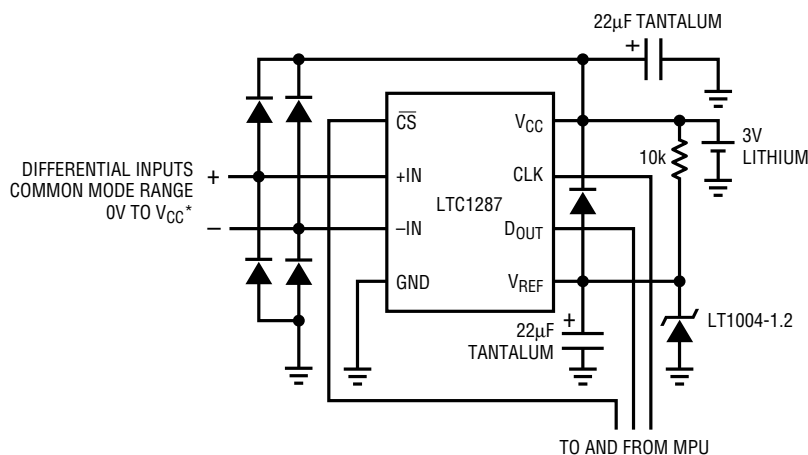
## DESCRIPTION

The LTC1287 is a 3V data acquisition component which contains a serial I/O successive approximation A/D converter. The device specifications are guaranteed at a supply voltage of 2.7V. It uses LTCMOS™ switched capacitor technology to perform a 12-bit unipolar, A/D conversion. The differential input has an on-chip sample-and-hold on the (+) input.

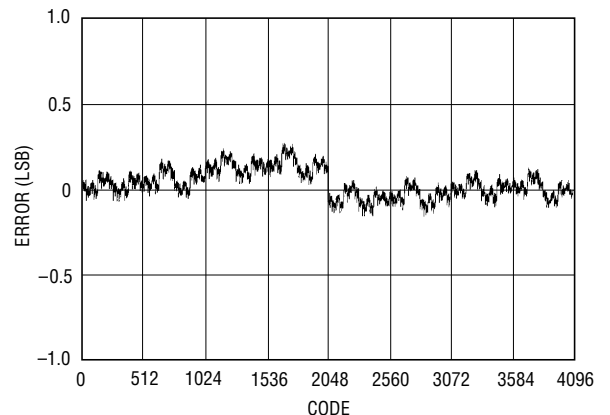
The serial I/O is designed to communicate without external hardware to most MPU serial ports and all MPU parallel I/O ports allowing data to be transmitted and received over three wires. The low voltage operating capability and the low power consumption of this device make it ideally suited for battery applications. Given the ease of use, small package size and the minimum number of interconnects for I/O, the LTC1287 can be used for remote sensing applications.

LTCMOS is a trademark of Linear Technology Corporation

**3V Differential Input Data Acquisition System**



**INL with  $V_{REF} = 1.2V$**



LTC1287 TA02

\* FOR OVERVOLTAGE PROTECTION, LIMIT THE INPUT CURRENT TO 15mA PER PIN OR CLAMP THE INPUTS TO  $V_{CC}$  AND GND WITH 1N4148 DIODES. CONVERSION RESULTS ARE NOT VALID WHEN THE SELECTED CHANNEL OR OTHER CHANNEL IS OVERVOLTAGED ( $V_{IN} < GND$  OR  $V_{IN} > V_{CC}$ ). SEE SECTION ON OVERVOLTAGE PROTECTION IN THE APPLICATIONS INFORMATION.

1287 TA01

## ABSOLUTE MAXIMUM RATINGS

(Notes 1 and 2)

Supply Voltage ( $V_{CC}$ ) to GND .....	12V
Voltage	
Analog and Reference Inputs ....	$-0.3V$ to $V_{CC} + 0.3V$
Digital Inputs .....	$-0.3V$ to $12V$
Digital Outputs .....	$-0.3V$ to $V_{CC} + 0.3V$
Power Dissipation .....	500mW
Operating Temperature Range	
LTC1287BI, LTC1287CI .....	$-40^{\circ}C$ TO $85^{\circ}C$
LTC1287BC, LTC1287CC .....	$0^{\circ}C$ to $70^{\circ}C$
Storage Temperature Range .....	$-65^{\circ}C$ to $150^{\circ}C$
Lead Temperature (Soldering, 10 sec.) .....	$300^{\circ}C$

## PACKAGE/ORDER INFORMATION

<p>TOP VIEW</p> <p>J8 PACKAGE 8-LEAD CERAMIC DIP</p> <p>N8 PACKAGE 8-LEAD PLASTIC DIP</p> <p>1287 PD</p>	ORDER PART NUMBER
	LTC1287BIJ LTC1287CIJ LTC1287BIN LTC1287CIN LTC1287BCJ LTC1287CCJ LTC1287BCN LTC1287CCN

## CONVERTER AND MULTIPLEXER CHARACTERISTICS (Note 3)

PARAMETER	CONDITIONS		LTC1287B			LTC1287C			UNITS
			MIN	TYP	MAX	MIN	TYP	MAX	
Offset Error	$V_{CC} = 2.7V$ (Note 4)	●			$\pm 3.0$			$\pm 3.0$	LSB
Linearity Error (INL)	$V_{CC} = 2.7V$ (Notes 4 & 5)	●			$\pm 0.5$			$\pm 0.5$	LSB
Gain Error	$V_{CC} = 2.7V$ (Note 4)	●			$\pm 0.5$			$\pm 1.0$	LSB
Minimum Resolution for Which No Missing Codes are Guaranteed		●			12			12	Bits
Analog and REF Input Range	(Note 7)				$(V^-) - 0.05V$ to $V_{CC} + 0.05V$				V
On Channel Leakage Current (Note 8)	On Channel = 3V Off Channel = 0V	●			$\pm 1$			$\pm 1$	$\mu A$
	On Channel = 0V Off Channel = 3V	●			$\pm 1$			$\pm 1$	$\mu A$
Off Channel Leakage Current (Note 8)	On Channel = 3V Off Channel = 0V	●			$\pm 1$			$\pm 1$	$\mu A$
	On Channel = 0V Off Channel = 3V	●			$\pm 1$			$\pm 1$	$\mu A$

## AC CHARACTERISTICS (Note 3)

SYMBOL	PARAMETER	CONDITIONS		LTC1287B/LTC1287C			UNITS	
				MIN	TYP	MAX		
$f_{CLK}$	Clock Frequency	(Note 6)		(Note 9)		0.5	MHz	
$t_{SMPL}$	Analog Input Sample Time	See Operating Sequence				1.5	CLK Cycles	
$t_{CONV}$	Conversion Time	See Operating Sequence				12	CLK Cycles	
$t_{CYC}$	Total Cycle Time	See Operating Sequence (Note 6)				14 CLK+ 5.0 $\mu s$	Cycles	
$t_{dDO}$	Delay Time, CLK $\downarrow$ to D <sub>OUT</sub> Data Valid	See Test Circuits	●			250	450	ns
$t_{dis}$	Delay Time, $\overline{CS}$ $\uparrow$ to D <sub>OUT</sub> Hi-Z	See Test Circuits	●			80	160	ns
$t_{en}$	Delay Time, CLK $\downarrow$ to D <sub>OUT</sub> Enabled	See Test Circuits	●			130	250	ns

**AC CHARACTERISTICS** (Note 3)

SYMBOL	PARAMETER	CONDITIONS	LTC1287B/LTC1287C			UNITS
			MIN	TYP	MAX	
$t_{hDO}$	Time Output Data Remains Valid After CLK $\downarrow$			50		ns
$t_f$	$D_{OUT}$ Fall Time	See Test Circuits	●	40	100	ns
$t_r$	$D_{OUT}$ Rise Time	See Test Circuits	●	40	100	ns
$t_{WHCLK}$	CLK High Time	$V_{CC} = 3V$ (Note 6)		600		ns
$t_{WLCLK}$	CLK Low Time	$V_{CC} = 3V$ (Note 6)		800		ns
$t_{su\overline{CS}}$	Setup Time, $\overline{CS}\downarrow$ Before CLK $\uparrow$	$V_{CC} = 3V$ (Note 6)		100		ns
$t_{WH\overline{CS}}$	$\overline{CS}$ High Time Between Data Transfer Cycles	$V_{CC} = 3V$ (Note 6)		5.0		$\mu s$
$t_{WL\overline{CS}}$	$\overline{CS}$ Low Time During Data Transfer	$V_{CC} = 3V$ (Note 6)		14		CLK Cycles
$C_{IN}$	Input Capacitance	Analog Inputs On Channel Analog Inputs Off Channel Digital Inputs		100 5 5		pF pF pF

**DIGITAL AND DC ELECTRICAL CHARACTERISTICS** (Note 3)

SYMBOL	PARAMETER	CONDITIONS	LTC1287B/LTC1287C			UNITS
			MIN	TYP	MAX	
$V_{IH}$	High Level Input Voltage	$V_{CC} = 3.6V$	●	2.1		V
$V_{IL}$	Low Level Input Voltage	$V_{CC} = 3.0V$	●		0.45	V
$I_{IH}$	High Level Input Current	$V_{IN} = V_{CC}$	●		2.5	$\mu A$
$I_{IL}$	Low Level Input Current	$V_{IN} = 0V$	●		-2.5	$\mu A$
$V_{OH}$	High Level Output Voltage	$V_{CC} = 3.0V$ , $I_O = 20\mu A$ $I_O = 400\mu A$	●	2.7	2.90 2.85	V V
$V_{OL}$	Low Level Output Voltage	$V_{CC} = 3.0V$ , $I_O = 20\mu A$ $I_O = 400\mu A$	●		0.05 0.10	V V
$I_{OZ}$	High Z Output Leakage	$V_{OUT} = V_{CC}$ , $\overline{CS}$ High $V_{OUT} = 0V$ , $\overline{CS}$ High	● ●		3 -3	$\mu A$ $\mu A$
$I_{SOURCE}$	Output Source Current	$V_{OUT} = 0V$			-10	mA
$I_{SINK}$	Output Sink Current	$V_{OUT} = V_{CC}$			9	mA
$I_{CC}$	Positive Supply Current	$\overline{CS}$ High	●	1.5	5	mA
$I_{REF}$	Reference Current	$V_{REF} = 2.5V$	●	10	50	$\mu A$

The ● denotes specifications which apply over the operating temperature range; all other limits and typicals  $T_A = 25^\circ C$ .

**Note 1:** Absolute Maximum Ratings are those values beyond which the life of a device may be impaired.

**Note 2:** All voltage values are with respect to ground (unless otherwise noted).

**Note 3:**  $V_{CC} = 3V$ ,  $V_{REF} = 2.5V$ , CLK = 500kHz unless otherwise specified.

**Note 4:** One LSB is equal to  $V_{REF}$  divided by 4096. For example, when  $V_{REF} = 2.5V$ ,  $1LSB = 2.5V/4096 = 0.61mV$ .

**Note 5:** Integral nonlinearity error is defined as the deviation of a code from a straight line passing through the actual endpoints of the transfer curve. The deviation is measured from the center of the quantization band.

**Note 6:** Recommended operating conditions.

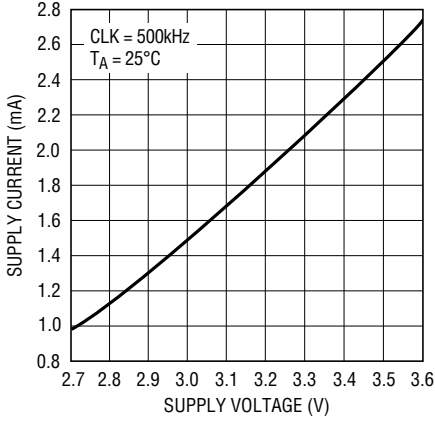
**Note 7:** Two on-chip diodes are tied to each analog input which will conduct for analog voltages one diode drop below GND or one diode drop above  $V_{CC}$ . Be careful during testing at low  $V_{CC}$  levels, as high level analog inputs can cause this input diode to conduct, especially at elevated temperature, and cause errors for inputs near full scale. This spec allows 50mV forward bias of either diode. This means that as long as the analog input does not exceed the supply voltage by more than 50mV, the output code will be correct.

**Note 8:** Channel leakage current is measured after the channel selection.

**Note 9:** Increased leakage currents at elevated temperatures cause the S/H to droop, therefore it is recommended that  $f_{CLK} \geq 30kHz$  at  $85^\circ C$  and  $f_{CLK} \geq 3kHz$  at  $25^\circ C$ .

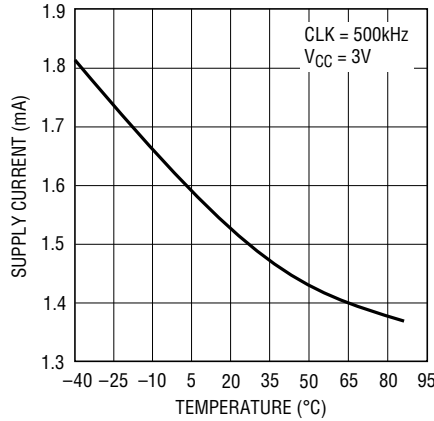
# TYPICAL PERFORMANCE CHARACTERISTICS

**Supply Current vs Supply Voltage**



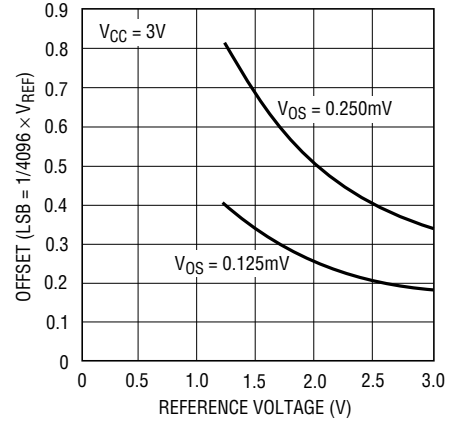
LTC1287 G1

**Supply Current vs Temperature**



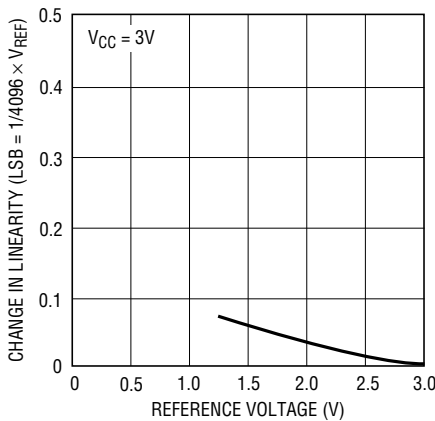
LTC1287 G2

**Unadjusted Offset Voltage vs Reference Voltage**



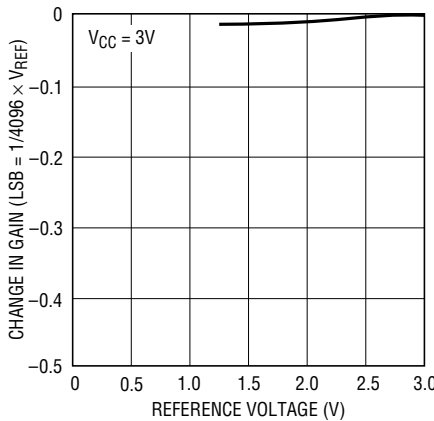
LTC1287 G3

**Change in Linearity vs Reference Voltage**



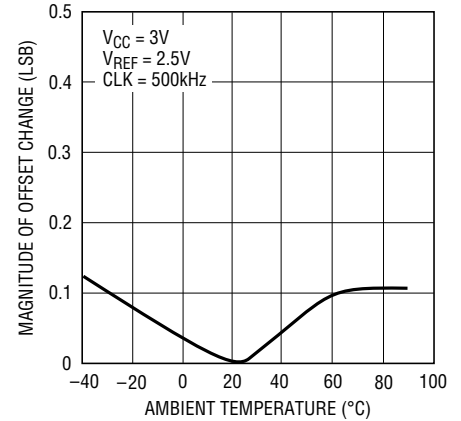
LTC1287 G4

**Change in Gain vs Reference Voltage**



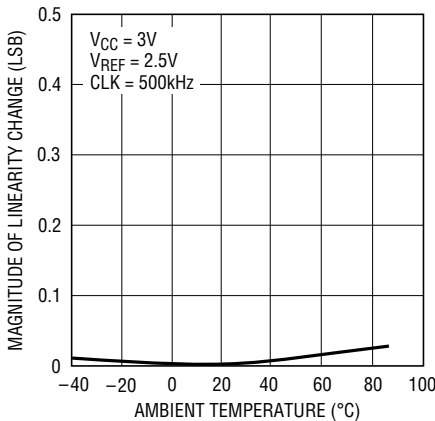
LTC1287 G5

**Change in Offset vs Temperature**



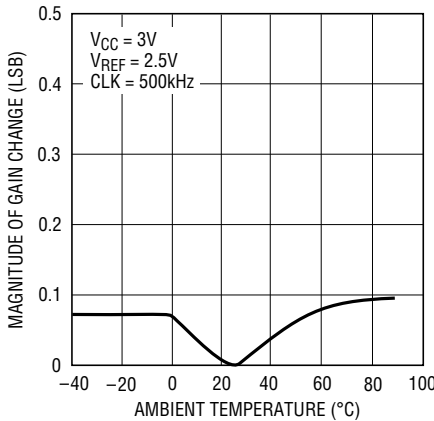
LTC1287 G6

**Change in Linearity vs Temperature**



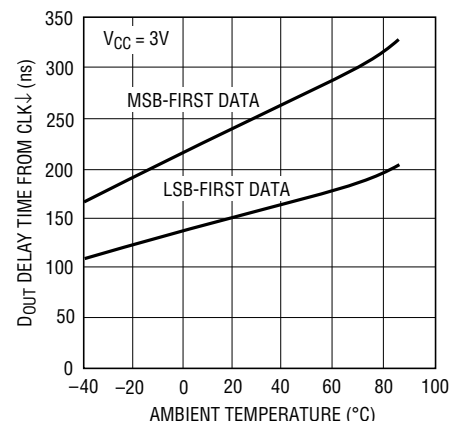
LTC1287 G7

**Change in Gain vs Temperature**



LTC1287 G8

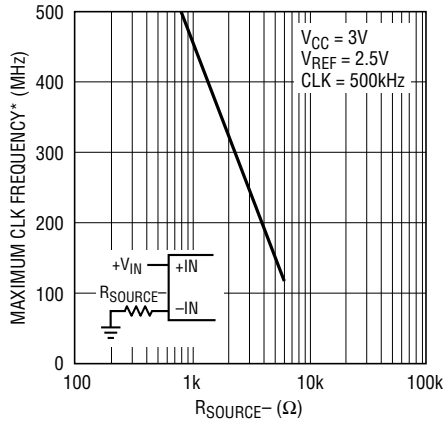
**DOUT Delay Time vs Temperature**



LTC1287 G9

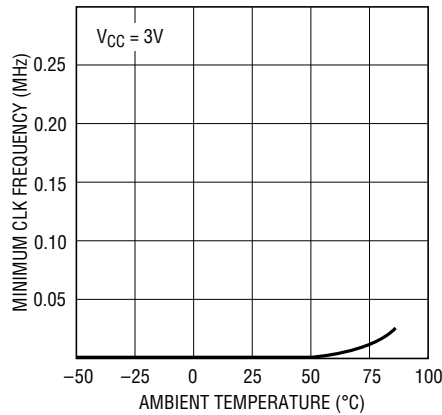
# TYPICAL PERFORMANCE CHARACTERISTICS

**Maximum Clock Rate vs Source Resistance**



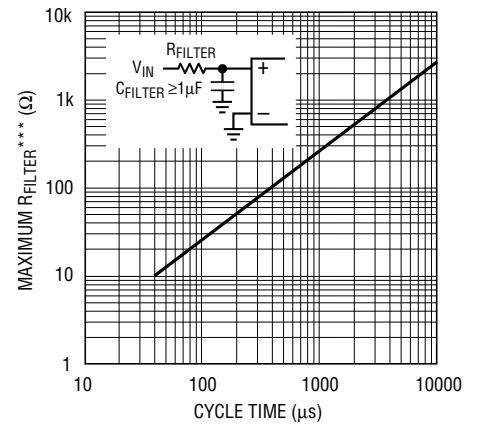
LTC G10

**Minimum Clock Rate for 0.1LSB Error\*\***



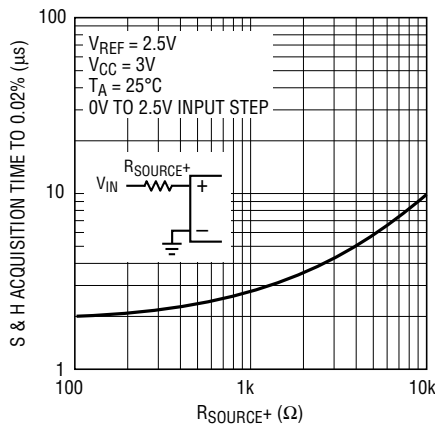
LTC1287 G11

**Maximum Filter Resistor vs Cycle Time**



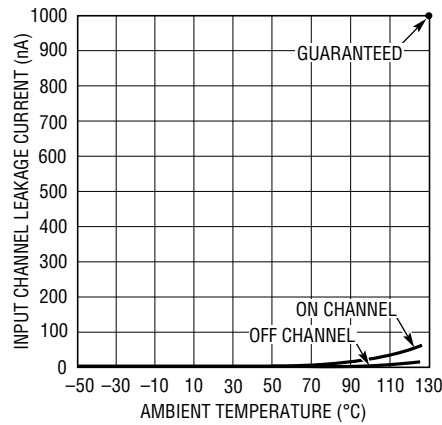
LTC1287 G12

**Sample-and-Hold Acquisition Time vs Source Resistance**



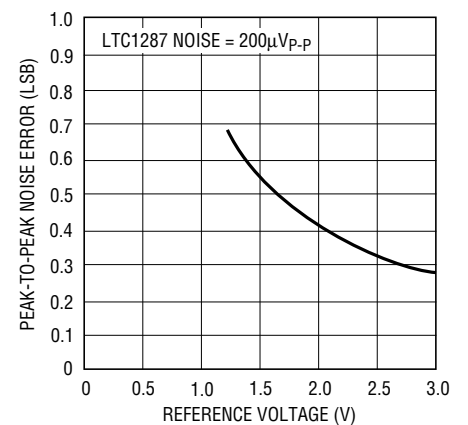
LTC1287 G13

**Input Channel Leakage Current vs Temperature**



LTC1287 G14

**Noise Error vs Reference Voltage**



LTC1287 G15

\* MAXIMUM CLK FREQUENCY REPRESENTS THE CLK FREQUENCY AT WHICH A 0.1LSB SHIFT IN THE ERROR AT ANY CODE TRANSITION FROM ITS 500kHz VALUE IS FIRST DETECTED.

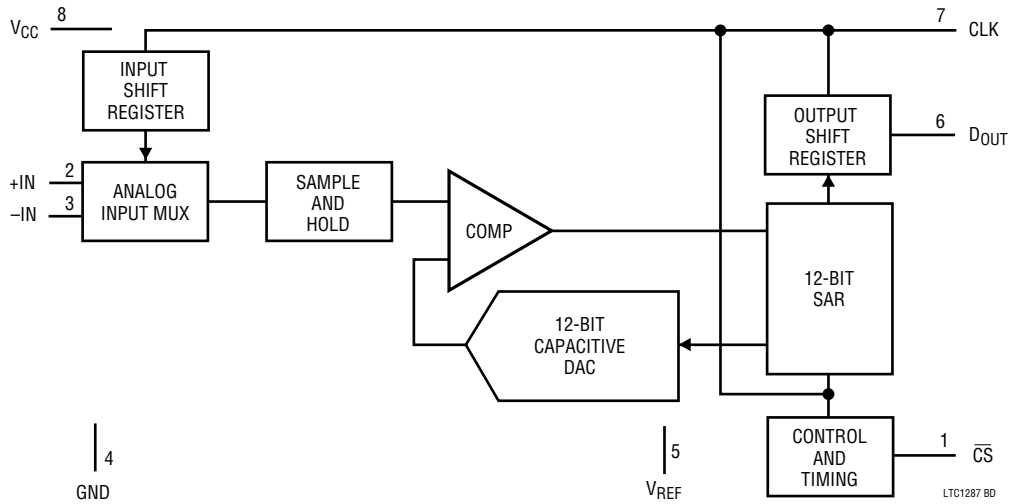
\*\*\* MAXIMUM  $R_{FILTER}$  REPRESENTS THE FILTER RESISTOR VALUE AT WHICH A 0.1LSB CHANGE IN FULL SCALE ERROR FROM ITS VALUE AT  $R_{FILTER} = 0\Omega$  IS FIRST DETECTED.

\*\* AS THE CLK FREQUENCY IS DECREASED FROM 1MHz, MINIMUM CLK FREQUENCY ( $\Delta ERROR \leq 0.1LSB$ ) REPRESENTS THE FREQUENCY AT WHICH A 0.1LSB SHIFT IN ANY CODE TRANSITION FROM ITS 500kHz VALUE IS FIRST DETECTED.

## PIN FUNCTIONS

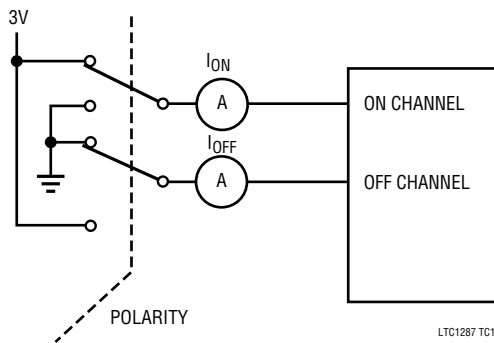
#	PIN	FUNCTION	DESCRIPTION
1	$\overline{CS}$	Chip Select Input	A logic low on this input enables the LTC1287.
2, 3	+IN, -IN	Analog Inputs	These inputs must be free of noise with respect to GND.
4	GND	Analog Ground	GND should be tied directly to an analog ground plane.
5	$V_{REF}$	Reference Input	The reference input defines the span of the A/D converter and must be kept free of noise with respect to GND.
6	$D_{OUT}$	Digital Data Output	The A/D conversion result is shifted out of this output.
7	CLK	Shift Clock	This clock synchronizes the serial data transfer.
8	$V_{CC}$	Positive Supply	This supply must be kept free of noise and ripple by bypassing directly to the analog ground plane.

# BLOCK DIAGRAM

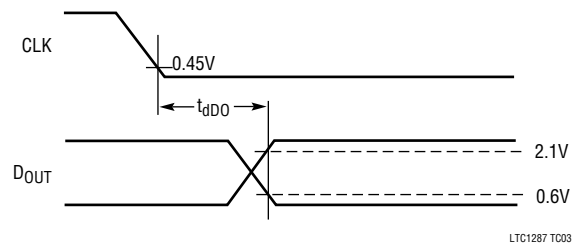


# TEST CIRCUITS

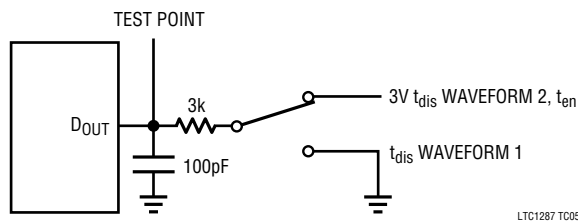
On and Off Channel Leakage Current



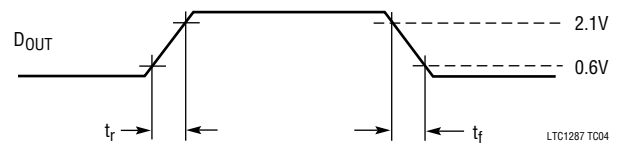
Voltage Waveforms for D<sub>OUT</sub> Delay Time, t<sub>dDO</sub>



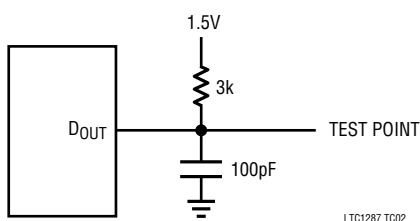
Load Circuit for t<sub>dis</sub> and t<sub>en</sub>



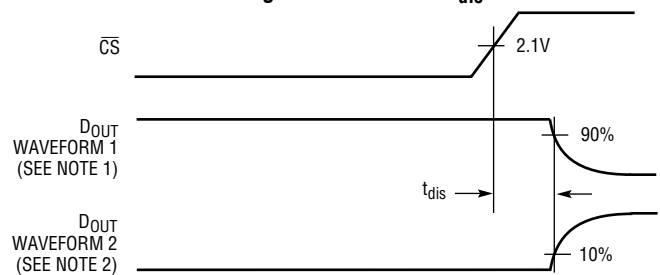
Voltage Waveforms for D<sub>OUT</sub> Rise and Fall Times, t<sub>r</sub>, t<sub>f</sub>



Load Circuit for t<sub>dDO</sub>, t<sub>r</sub> and t<sub>f</sub>

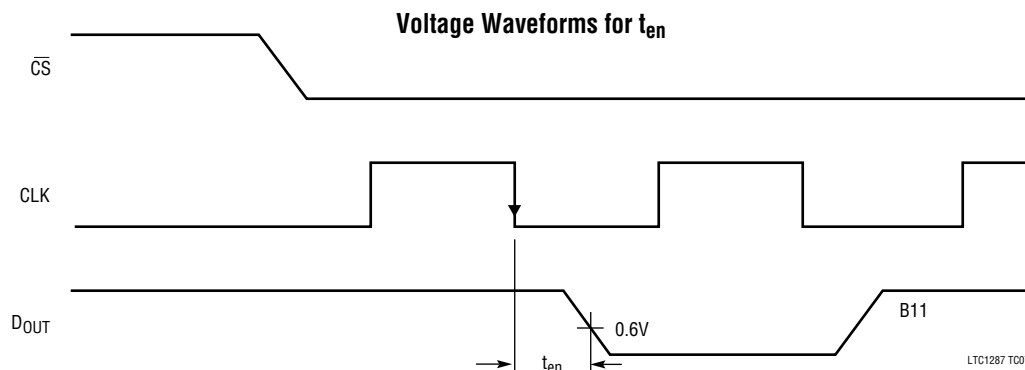


Voltage Waveforms for t<sub>dis</sub>



NOTE 1: WAVEFORM 1 IS FOR AN OUTPUT WITH INTERNAL CONDITIONS SUCH THAT THE OUTPUT IS HIGH UNLESS DISABLED BY THE OUTPUT CONTROL.  
NOTE 2: WAVEFORM 2 IS FOR AN OUTPUT WITH INTERNAL CONDITIONS SUCH THAT THE OUTPUT IS LOW UNLESS DISABLED BY THE OUTPUT CONTROL.

## TEST CIRCUITS



## APPLICATIONS INFORMATION

The LTC1287 is a data acquisition component which contains the following functional blocks:

1. 12-bit successive approximation capacitive A/D converter
2. Analog multiplexer (MUX)
3. Sample-and-hold (S/H)
4. Synchronous, half-duplex serial interface
5. Control and timing logic

### DIGITAL CONSIDERATIONS

#### Serial Interface

The LTC1287 communicates with microprocessors and other external circuitry via a synchronous, half-duplex, three-wire serial interface (see Operating Sequence). The clock (CLK) synchronizes the data transfer with each bit being transmitted on the falling CLK edge. The LTC1287

does not require a configuration input word and has no  $D_{IN}$  pin. It is permanently configured to have a single differential input and to operate in unipolar mode. A falling  $\overline{CS}$  initiates data transfer. The first CLK pulse enables  $D_{OUT}$ . After one null bit, the A/D conversion result is output on the  $D_{OUT}$  line with a MSB-first sequence followed by a LSB-first sequence. With the half duplex serial interface the  $D_{OUT}$  data is from the current conversion. This provides easy interface to MSB- or LSB-first serial ports. Bringing  $\overline{CS}$  high resets the LTC1287 for the next data exchange.

#### Logic Levels

The logic level standards for this supply range have not been well defined. What standards that do exist are not universally accepted. The trip point on the logic inputs of the LTC1287 is  $0.28 \times V_{CC}$ . This makes the logic inputs compatible with HC-type levels and processors that are

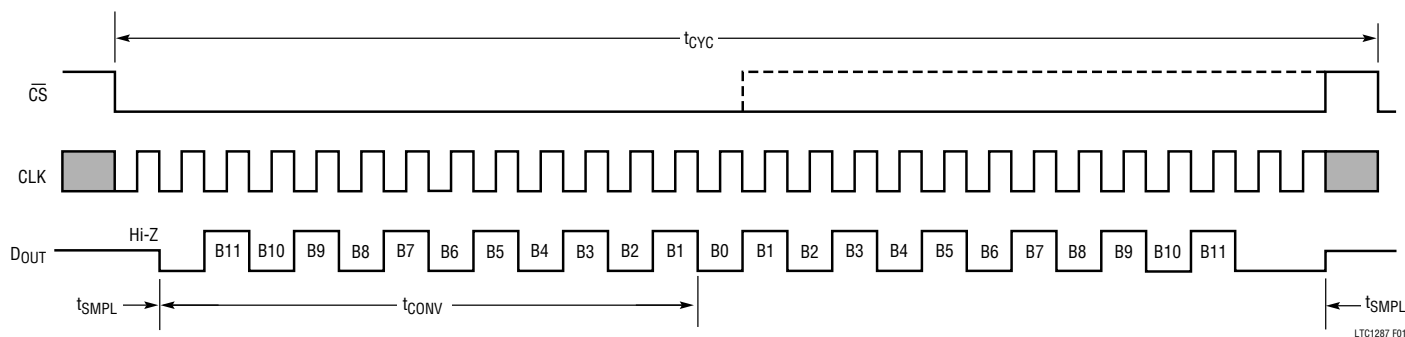


Figure 1. LTC1287 Operating Sequence

## APPLICATIONS INFORMATION

specified at 3.3V. The output  $D_{OUT}$  is also compatible with the above standards. The following summarizes such levels.

$V_{OH}$ (no load)	$V_{CC} - 0.1V$
$V_{OL}$ (no load)	0.1V
$V_{OH}$	$0.9 \times V_{CC}$
$V_{OL}$	$0.1 \times V_{CC}$
$V_{IH}$	$0.7 \times V_{CC}$
$V_{IL}$	$0.2 \times V_{CC}$

The LTC1287 can be driven with 5V logic even when  $V_{CC}$  is at 3.3V. This is due to a unique input protection device that is found on the LTC1287.

### Microprocessor Interfaces

The LTC1287 can interface directly (without external hardware) to most popular microprocessor (MPU) synchronous serial formats. If an MPU without a serial interface is used, then three of the MPU's parallel port lines can be programmed to form the serial link to the LTC1287. Many of the popular MPUs can operate with 3V supplies. For example the MC68HC11 is an MPU with a serial format (SPI). Likewise parallel MPUs that have the 8051 type architecture are also capable of operating at this voltage range. The code for these processors remains the same and can be found in the LTC1292 data sheet.

### Sharing the Serial Interface

The LTC1287 can share the same two-wire serial interface with other peripheral components or other LTC1287s (Figure 2). In this case, the  $\overline{CS}$  signals decide which LTC1287 is being addressed by the MPU.

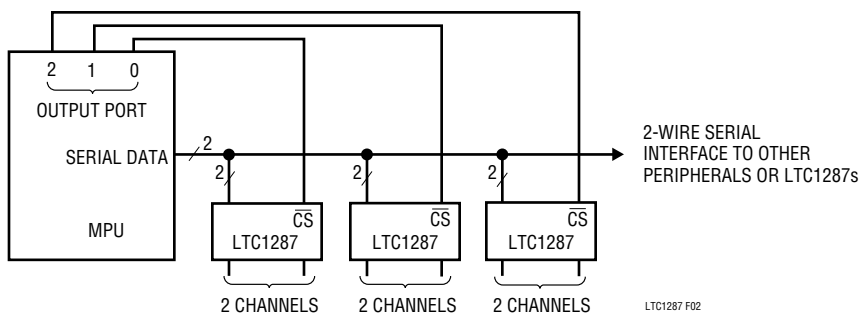


Figure 2. Several LTC1287s Sharing One 2-Wire Serial Interface

## ANALOG CONSIDERATIONS

### Grounding

The LTC1287 should be used with an analog ground plane and single point grounding techniques. Do not use wire wrapping techniques to breadboard and evaluate the device. To achieve the optimum performance use a PC board. The ground pin (Pin 4) should be tied directly to the ground plane with minimum lead length (a low profile socket is fine). Pin 7 ( $V_{CC}$ ) should be bypassed to the ground plane with a 22 $\mu$ F (minimum value) tantalum with leads as short as possible and as close as possible to the pin. A 0.1 $\mu$ F ceramic disk also should be placed in parallel with the 22 $\mu$ F and again with leads as short as possible and as close to  $V_{CC}$  as possible. Figure 3 shows an example of an ideal LTC1287 ground plane design for a two-sided board. Of course this much ground plane will not always be possible, but users should strive to get as close to this ideal as possible.

### Bypassing

For good performance,  $V_{CC}$  must be free of noise and ripple. Any changes in the  $V_{CC}$  voltage with respect to ground during a conversion cycle can induce errors or noise in the output code.  $V_{CC}$  noise and ripple can be kept below 0.5mV by bypassing the  $V_{CC}$  pin directly to the analog plane with a minimum of 22 $\mu$ F tantalum capacitor and with leads as short as possible. The lead from the device to the  $V_{CC}$  supply also should be kept to a minimum and the  $V_{CC}$  supply should have a low output impedance

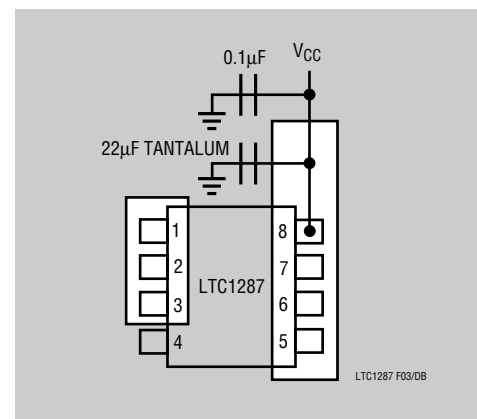


Figure 3. Example Ground Plane for the LTC1287

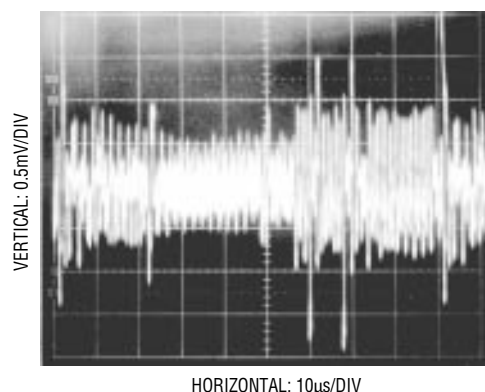


## APPLICATIONS INFORMATION

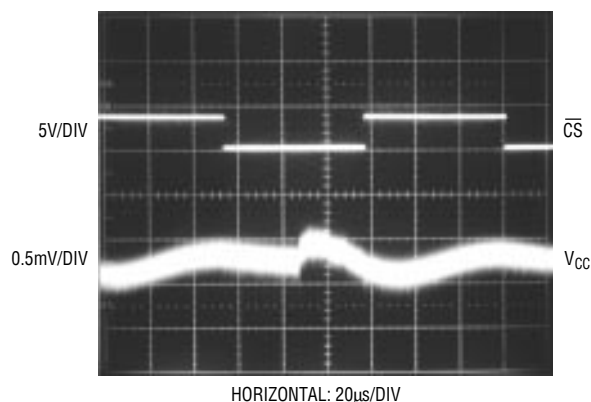
such as obtained from a voltage regulator (e.g., LT1117). For high frequency bypassing a  $0.1\mu\text{F}$  ceramic disk placed in parallel with the  $22\mu\text{F}$  is recommended. Again the leads should be kept to a minimum. Using a battery to power the LTC1287 will help reduce the amount of bypass capacitance required on the  $V_{\text{CC}}$  pin. A battery placed close to the device will only require  $10\mu\text{F}$  to adequately bypass the supply pin. Figure 4 shows the effect of poor  $V_{\text{CC}}$  bypassing. Figure 5 shows the settling of a LT1117 low dropout regulator with a  $22\mu\text{F}$  bypass capacitor. The noise and ripple is kept around  $0.5\text{mV}$ . Figure 6 shows the response of a lithium battery with a  $10\mu\text{F}$  bypass capacitor. The noise and ripple is kept below  $0.5\text{mV}$ .

### Analog Inputs

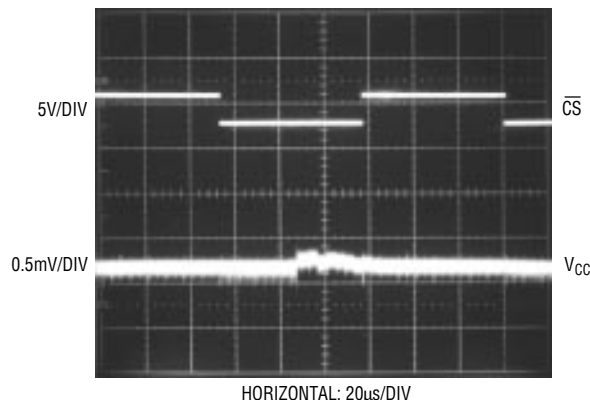
Because of the capacitive redistribution A/D conversion techniques used, the analog inputs of the LTC1287 have



**Figure 4. Poor  $V_{\text{CC}}$  Bypassing. Noise and Ripple Can Cause A/D Errors**



**Figure 5. LT1117 Regulator with  $22\mu\text{F}$  Bypassing on  $V_{\text{CC}}$**

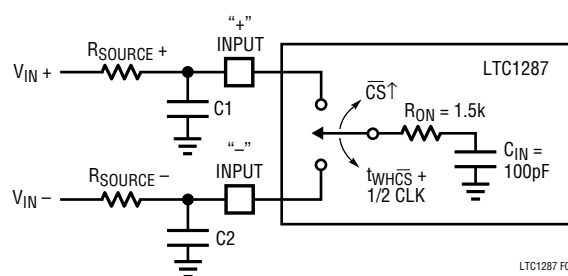


**Figure 6. Lithium Battery with  $10\mu\text{F}$  Bypassing on  $V_{\text{CC}}$**

capacitive switching input current spikes. These current spikes settle quickly and do not cause a problem. If large source resistances are used or if slow settling op amps drive the inputs, take care to insure the transients caused by the current spikes settle completely before the conversion begins.

### Source Resistance

The analog inputs of the LTC1287 look like a  $100\text{pF}$  capacitor ( $C_{\text{IN}}$ ) in series with a  $1.5\text{k}$  resistor ( $R_{\text{ON}}$ ). This value for  $R_{\text{ON}}$  is for  $V_{\text{CC}} = 2.7\text{V}$ . With larger supply voltages  $R_{\text{ON}}$  will be reduced. For example, with  $V_{\text{CC}} = 2.7\text{V}$  and  $V^- = -2.7\text{V}$ ,  $R_{\text{ON}}$  becomes  $500\Omega$ .  $C_{\text{IN}}$  gets switched between (+) and (-) inputs once during each conversion cycle. Large external source resistors and capacitances will slow the settling of the inputs. It is important that the overall RC time constant is short enough to allow the analog inputs to settle completely within the allowed time.



**Figure 7. Analog Input Equivalent Circuit**

## APPLICATIONS INFORMATION

### “+” Input Settling

The input capacitor is switched onto the “+” input during the sample phase ( $t_{SMPL}$ , see Figures 8a, 8b and 8c). The sample period can be as short as  $t_{WHCS} + 0.5$  CLK cycle or as long as  $t_{WHCS} + 1.5$  CLK cycles before a conversion starts. This variability depends on where  $\overline{CS}$  falls relative to CLK. The voltage on the “+” input must settle completely within the sample period. Minimizing  $R_{SOURCE+}$  and C1 will improve the settling time. If large “+” input source

resistance must be used, the sample time can be increased by using a slower CLK frequency. With the minimum possible sample time of  $6.0\mu s$ ,  $R_{SOURCE+} < 4.0k$  and  $C1 < 20pF$  will provide adequate settle time.

### “-” Input Settling

At the end of the sample phase the input capacitor switches to the “-” input and the conversion starts (see Figures 8a, 8b and 8c). During the conversion, the “+” input voltage is

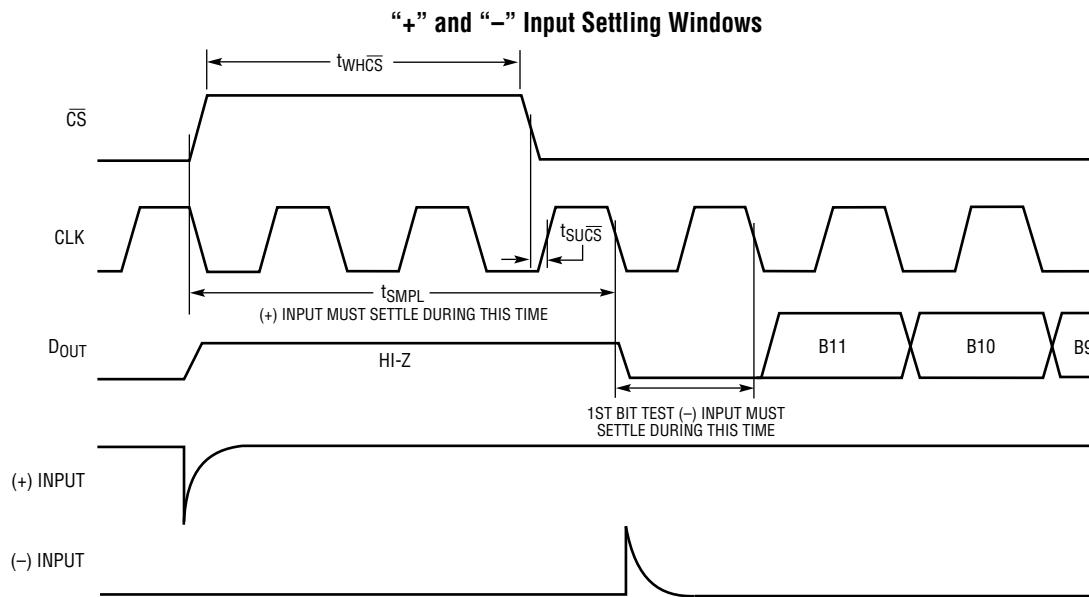


Figure 8a. Setup Time ( $t_{SU\overline{CS}}$ ) is Met

LTC1287 F8a

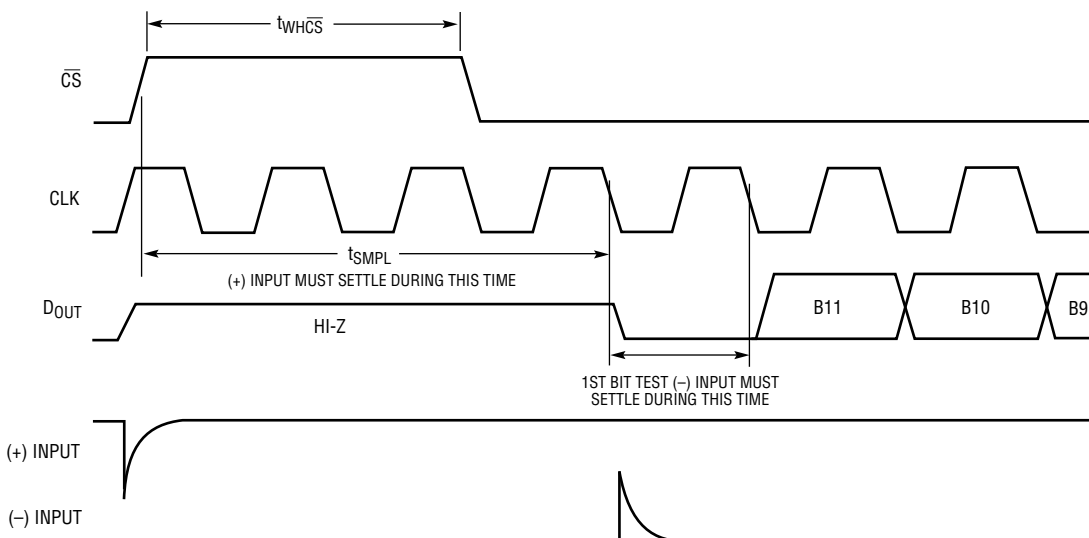


Figure 8b. Setup Time ( $t_{SU\overline{CS}}$ ) is Met

LTC1287 F8b

## APPLICATIONS INFORMATION

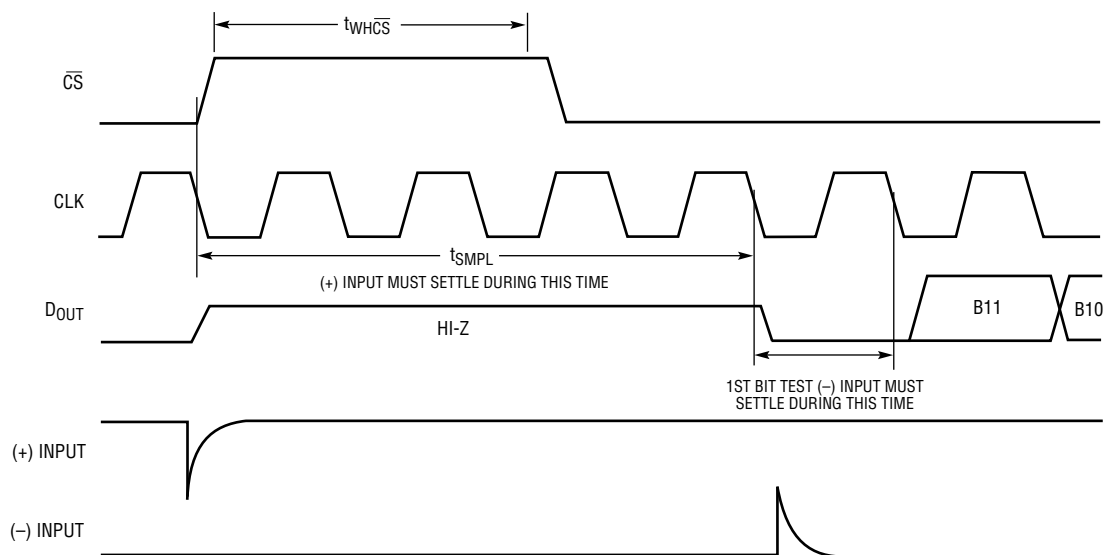


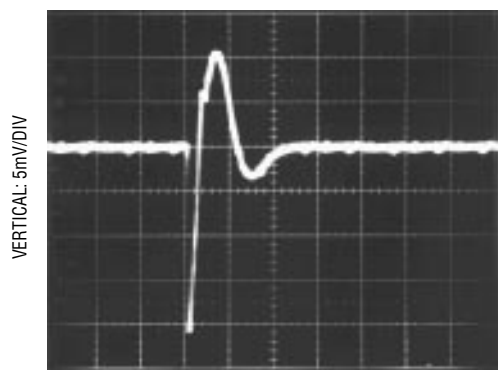
Figure 8c. Setup Time ( $t_{SU\overline{CS}}$ ) is Not Met

effectively “held” by the sample and hold and will not affect the conversion result. It is critical that the “-” input voltage be free of noise and settle completely during the first CLK cycle of the conversion. Minimizing  $R_{SOURCE-}$  and  $C2$  will improve settling time. If large “-” input source resistance must be used the time can be extended by using a slower CLK frequency. At the maximum CLK frequency of 500kHz,  **$R_{SOURCE-} < 200\Omega$  and  $C2 < 20pF$  will provide adequate settling.**

### Input Op Amps

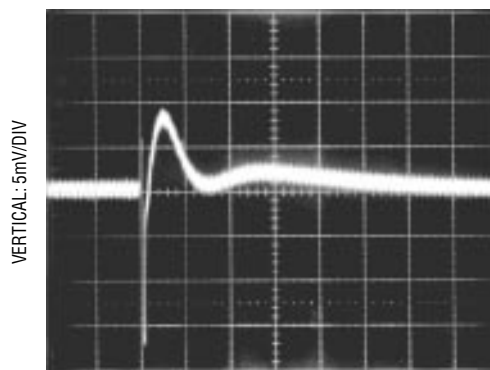
When driving the analog inputs with an op amp it is important that the op amp settles within the allowed time

(see Figures 8a, 8b and 8c). Again the “+” and “-” input sampling times can be extended as described above to accommodate slower op amps. For single supply low voltage application the LT1006, LT1013 and LT1014 can be made to settle well even with the minimum settling windows of  $6\mu s$  (“+” input) and  $2\mu s$  (“-” input) which occur at the maximum clock rates ( $CLK = 500kHz$ ). Figures 9 and 10 show examples of adequate and poor op amp settling. The LT1077, LT1078 or LT1079 can be used here to reduce power consumption. Placing an RC network at the output of the op amps will improve the settling response and also reduce the broadband noise.



HORIZONTAL: 500ns/DIV

Figure 9. Adequate Settling of Op Amp Driving Analog Input



HORIZONTAL: 20µs/DIV

Figure 10. Poor Op Amp Settling Can Cause A/D Errors

## APPLICATIONS INFORMATION

### RC Input filtering

It is possible to filter the inputs with an RC network as shown in Figure 11. For large values of  $C_F$  (e.g.,  $1\mu\text{F}$ ) the capacitive input switching currents are averaged into a net DC current. A filter should be chosen with a small resistor and large capacitor to prevent DC drops across the resistor. The magnitude of the DC current is approximately  $I_{DC} = 100\text{pF} \times V_{IN}/t_{CYC}$  and is roughly proportional to  $V_{IN}$ . When running at the minimum cycle time of  $33\mu\text{s}$ , the input current equals  $7.6\mu\text{A}$  at  $V_{IN} = 2.5\text{V}$ . Here a filter resistor of  $8\Omega$  will cause  $0.1\text{LSB}$  of full-scale error. If a large filter resistor must be used, errors can be reduced by increasing the cycle time as shown in the Typical Performance Characteristics curve Maximum Filter Resistor vs Cycle Time.

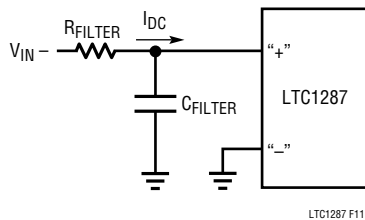


Figure 11. RC Input Filtering

### Input Leakage Current

Input leakage currents also can create errors if the source resistance gets too large. For example, the maximum input leakage specification of  $1\mu\text{A}$  (at  $85^\circ\text{C}$ ) flowing through a source resistance of  $1\text{k}$  will cause a voltage drop of  $1\text{mV}$  or  $1.6\text{LSB}$  with  $V_{REF} = 2.5\text{V}$ . This error will be much reduced at lower temperatures because leakage drops rapidly (see Typical Performance Characteristics curve Input Channel Leakage Current vs Temperature).

## SAMPLE-AND-HOLD

### Single-Ended Input

The LTC1287 provides a built-in sample and hold (S&H) function on the +IN input for signals acquired in the single ended mode (-IN pin grounded). The sample and hold allows the LTC1287 to convert rapidly varying signals (see Typical Performance Characteristics curve of S&H

Acquisition Time vs Source Resistance). The input voltage is sampled during the  $t_{SAMPL}$  time as shown in Figure 8. The sampling interval begins at rising edge of CS and continues until the falling edge of the CLK before the conversion begins. On this falling edge the S&H goes into the hold mode and the conversion begins.

### Differential Input

With a differential input the A/D no longer converts a single voltage but converts the difference between two voltages. The voltage on the +IN pin is sampled and held and can be rapidly time varying. The voltage on the -IN pin must remain constant and be free of noise and ripple throughout the conversion time. Otherwise the differencing operation will not be done accurately. The conversion time is 12 CLK cycles. Therefore a change in the -IN input voltage during this interval can cause conversion errors. For a sinusoidal voltage on the -IN input this error would be:

$$V_{\text{ERROR(MAX)}} = \left(2\pi f_{(-\text{IN})} V_{\text{PEAK}}\right) \left(\frac{12}{f_{\text{CLK}}}\right)$$

Where  $f_{(-\text{IN})}$  is the frequency of the -IN input voltage,  $V_{\text{PEAK}}$  is its peak amplitude and  $f_{\text{CLK}}$  is the frequency of the CLK. Usually  $V_{\text{ERROR}}$  will not be significant. For a  $60\text{Hz}$  signal on the -IN input to generate a  $0.25\text{LSB}$  error ( $150\mu\text{V}$ ) with the converter running at  $\text{CLK} = 500\text{kHz}$ , its peak value would have to be  $16\text{mV}$ . Rearranging the above equation, the maximum sinusoidal signal that can be digitized to a given accuracy is given as:

$$f_{(-\text{IN})\text{MAX}} = \left(\frac{V_{\text{ERROR(MAX)}}}{2\pi V_{\text{PEAK}}}\right) \left(\frac{f_{\text{CLK}}}{12}\right)$$

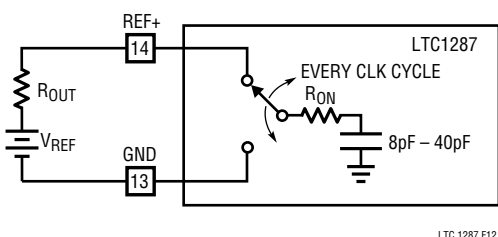
For  $0.25\text{LSB}$  error ( $150\mu\text{V}$ ) the maximum input sinusoid with a  $2.5\text{V}$  peak amplitude that can be digitized is  $0.4\text{Hz}$ .

### Reference Input

The voltage on the reference input of the LTC1287 determines the voltage span of the A/D converter. The reference input has transient capacitive switching currents due to the switched capacitor conversion technique (see Figure 12). During each bit test of the

## APPLICATIONS INFORMATION

conversion (every CLK cycle) a capacitive current spike will be generated on the reference pin by the A/D. These current spikes settle quickly and do not cause a problem. If slow settling circuitry is used to drive the reference input, take care to insure that transients caused by these current spikes settle completely during each bit test of the conversion.



LTC 1287 F12

Figure 12. Reference Input Equivalent Circuit

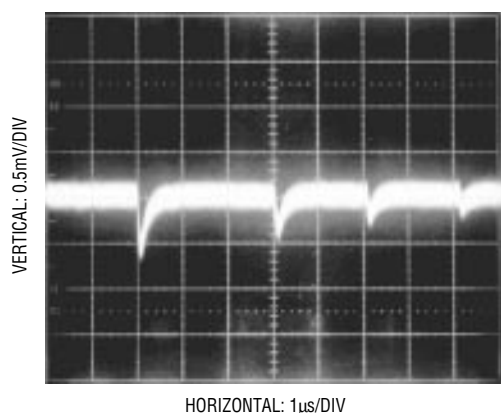


Figure 13. Adequate Reference Settling

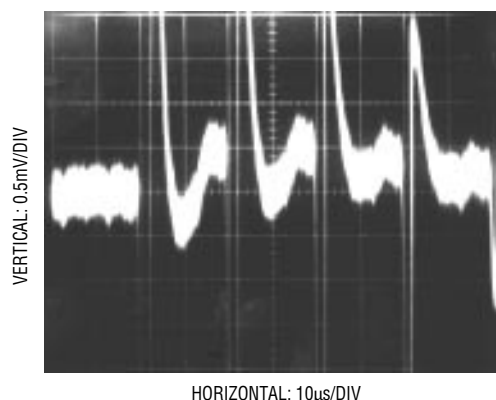


Figure 14. Poor Reference Settling Can Cause A/D Errors

Figures 13 and 14 show examples of both adequate and poor settling. Using a slower CLK will allow more time for the reference to settle. Even at the maximum CLK rate of 500kHz most references and op amps can be made to settle within the  $2\mu\text{s}$  bit time. For example an LT1019 used in the shunt mode with a  $10\mu\text{F}$  bypass capacitor will settle adequately. To minimize power an LT1004-2.5 can be used with a  $10\mu\text{F}$  bypass capacitor. For lower value references the LT1004-1.2 with a  $10\mu\text{F}$  bypass capacitor can be used.

### Reduced Reference Operation

The effective resolution of the LTC1287 can be increased by reducing the input span of the converter. The LTC1287 exhibits good linearity over a range of reference voltages (see Typical Performance Characteristics curves of Change in Linearity vs Reference Voltage). Care must be taken when operating at low values of  $V_{\text{REF}}$  because of the reduced LSB step size and the resulting higher accuracy requirement placed on the converter. Offset and Noise are factors that must be considered when operating at low  $V_{\text{REF}}$  values.

### Offset with Reduced $V_{\text{REF}}$

The offset of the LTC1287 has a larger effect on the output code when the A/D is operated with a reduced reference voltage. The offset (which is typically a fixed voltage) becomes a larger fraction of an LSB as the size of the LSB is reduced. The Typical Performance Characteristics curve of Unadjusted Offset Error vs Reference Voltage shows how offset in LSBs is related to reference voltage for a typical value of  $V_{\text{OS}}$ . For example a  $V_{\text{OS}}$  of 0.1mV, which is 0.2LSB with a 2.5V reference becomes 0.4LSB with a 1.25 reference. If this offset is unacceptable, it can be corrected digitally by the receiving system or by offsetting the  $-\text{IN}$  input to the LTC1287.

### Noise with Reduced $V_{\text{REF}}$

The total input referred noise of the LTC1287 can be reduced to approximately  $200\mu\text{V}$  peak-to-peak using a ground plane, good bypassing, good layout techniques and minimizing noise on the reference inputs. This

## APPLICATIONS INFORMATION

noise is insignificant with a 2.5V reference input but will become a larger fraction of an LSB as the size of the LSB is reduced. The Typical Performance Characteristics curve of Noise Error vs Reference Voltage shows the LSB contribution of this 200 $\mu$ V of noise.

For operation with a 2.5V reference, the 200 $\mu$ V noise is only 0.32LSB peak-to-peak. Here the LTC1287 noise will contribute virtually no uncertainty to the output code. For reduced references, the noise may become a significant fraction of an LSB and cause undesirable jitter in the output code. For example, with a 1.25V reference, this 200 $\mu$ V noise is 0.64LSB peak-to-peak. This will reduce the range of input voltages over which a stable output code can be achieved by 0.64LSB. Now averaging readings may be necessary.

This noise data was taken in a very clean test fixture. Any setup induced noise (noise or ripple on  $V_{CC}$ ,  $V_{REF}$  or  $V_{IN}$ ) will add to the internal noise. The lower the reference voltage used, the more critical it becomes to have a noise-free setup.

### Overvoltage Protection

Applying signals to the LTC1287's analog inputs that exceed the positive supply or that go below ground will degrade the accuracy of the A/D and possibly damage the device. For example this condition would occur if a signal is applied to the analog inputs before power is applied to the LTC1287. Another example is the input source operating from different supplies of larger value than the LTC1287. These conditions should be prevented either with proper supply sequencing or by use of external circuitry to clamp or current limit the input source. There are two ways to protect the inputs. In Figure 15 diode clamps from the inputs to  $V_{CC}$  and GND are used. The second method is to put resistors in series with the analog inputs for current limiting. Limit the current to 15mA per channel. The +IN input can accept a resistor value of 1k but the -IN input cannot accept more than 200 $\Omega$  when clocked at its maximum clock frequency of 500kHz. If the LTC1287 is clocked at the maximum clock frequency and 200 $\Omega$  is not enough to current limit the input source then the clamp diodes are recommended (Figures 16 and 17). The reason for

the limit on the resistor value is the MSB bit test is affected by the value of the resistor placed at the -IN input (see discussion on Analog Inputs and the Typical Performance Characteristics curve of Maximum CLK Frequency vs Source Resistance).

If  $V_{CC}$  and  $V_{REF}$  are not tied together, then  $V_{CC}$  should be turned on first, then  $V_{REF}$ . If this sequence cannot be met, connecting a diode from  $V_{REF}$  to  $V_{CC}$  is recommended (see Figure 18).

Because a unique input protection structure is used on the digital input pins, the signal levels on these pins can exceed the device  $V_{CC}$  without damaging the device.

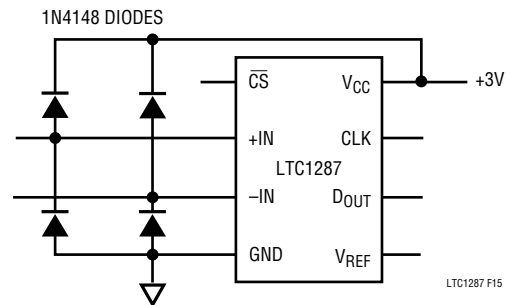


Figure 15. Overvoltage Protection for Inputs

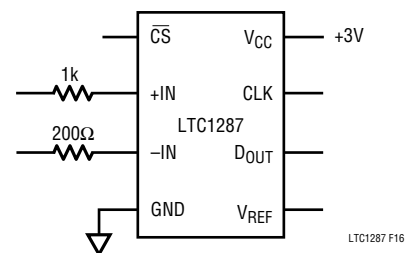


Figure 16. Overvoltage Protection for Inputs

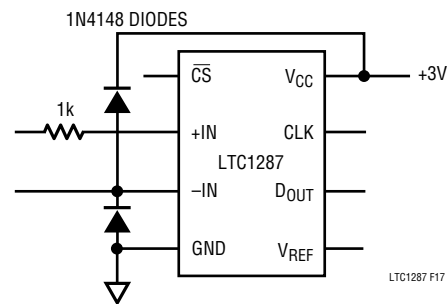


Figure 17. Overvoltage Protection for Inputs



## APPLICATIONS INFORMATION

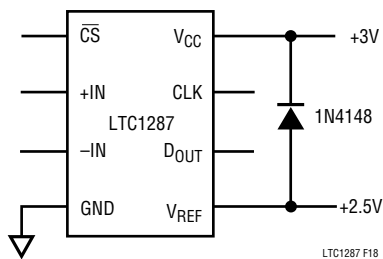


Figure 18

### A “Quick Look” Circuit for the LTC1287

Users can get a quick look at the function and timing of the LTC1287 by using the following simple circuit (Figure 19).  $V_{REF}$  is tied to  $V_{CC}$ .  $V_{IN}$  is applied to the +IN input and the -IN input is tied to the ground plane.  $\overline{CS}$  is driven at  $1/32$  the clock rate by the 74HC393 and  $D_{OUT}$  outputs the data. The output data from the  $D_{OUT}$  pin can be viewed on an oscilloscope that is set up to trigger on the falling edge of  $\overline{CS}$  (Figure 20). Note the LSB data is partially clocked out before  $\overline{CS}$  goes high.

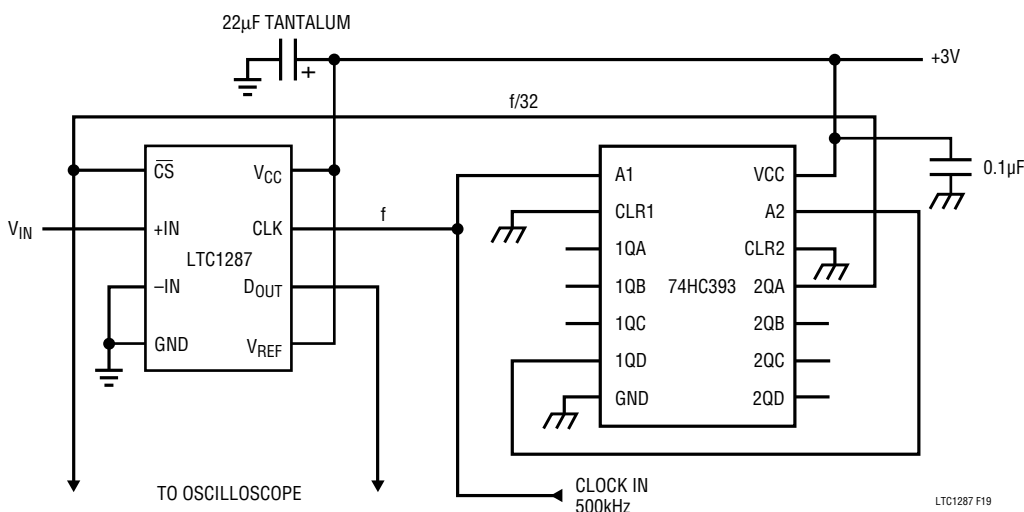


Figure 19. “Quick Look” Circuit for the LTC1287

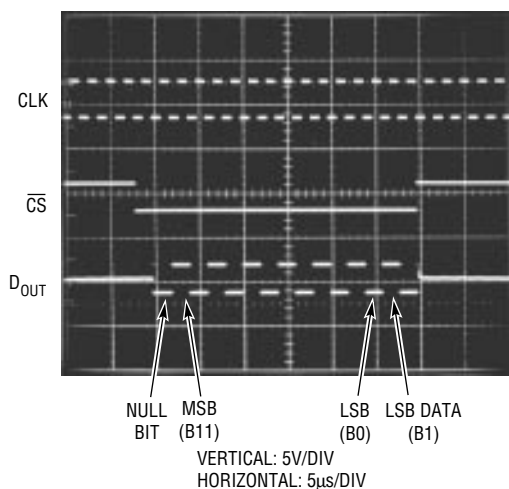
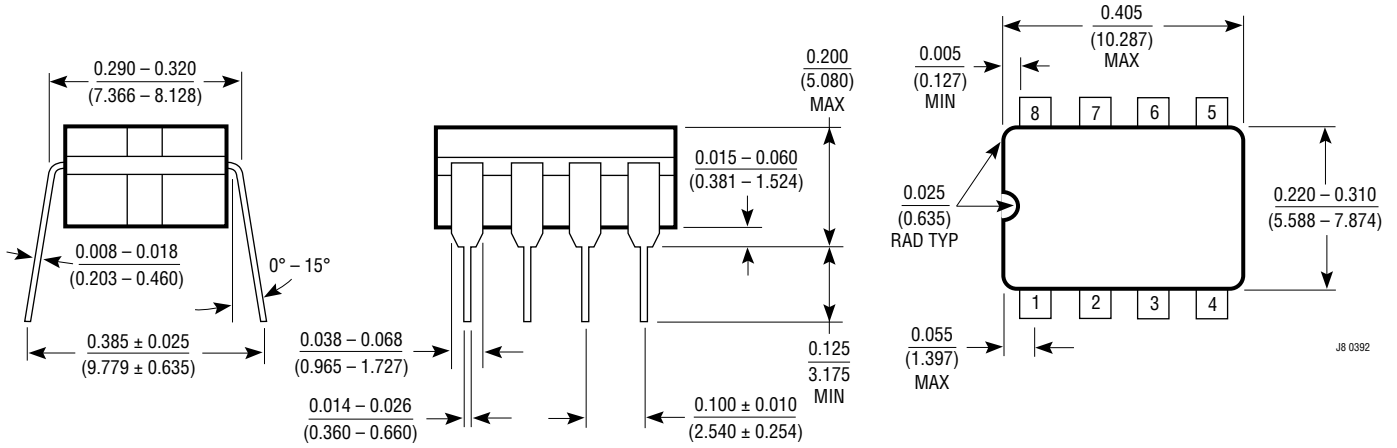


Figure 20. Scope Trace of the LTC1287 “Quick Look” Circuit Showing A/D Output 10101010 (AAA<sub>HEX</sub>)

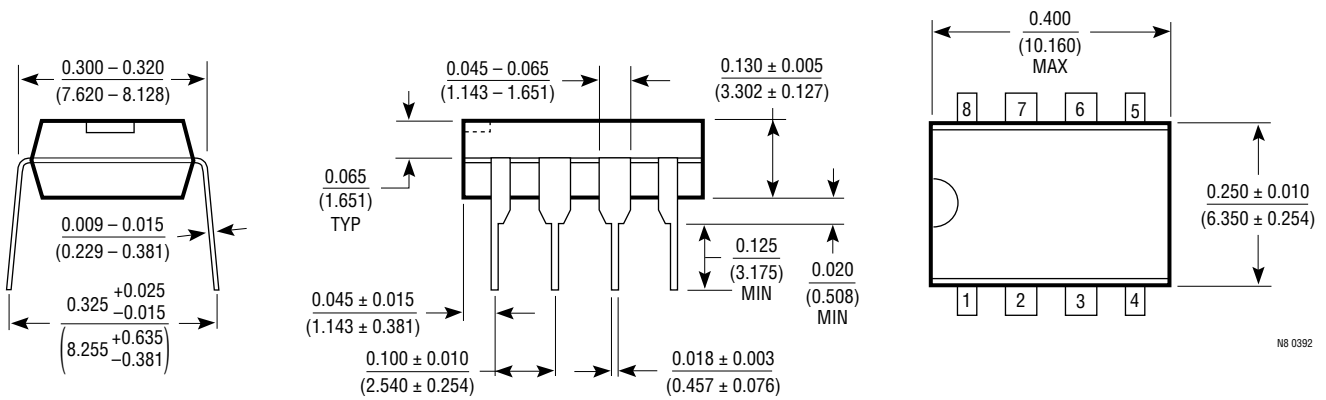
**PACKAGE DESCRIPTION** Dimensions in inches (millimeters) unless otherwise noted.

**J8 Package  
8-Lead Ceramic DIP**



T <sub>JMAX</sub>	θ <sub>JA</sub>
150°C	100°C/W

**N8 Package  
8-Lead Plastic DIP**



T <sub>JMAX</sub>	θ <sub>JA</sub>
100°C	130°C/W